

Figure 1. Samples structure and RHEED patterns observed at different stages of AlN growth.

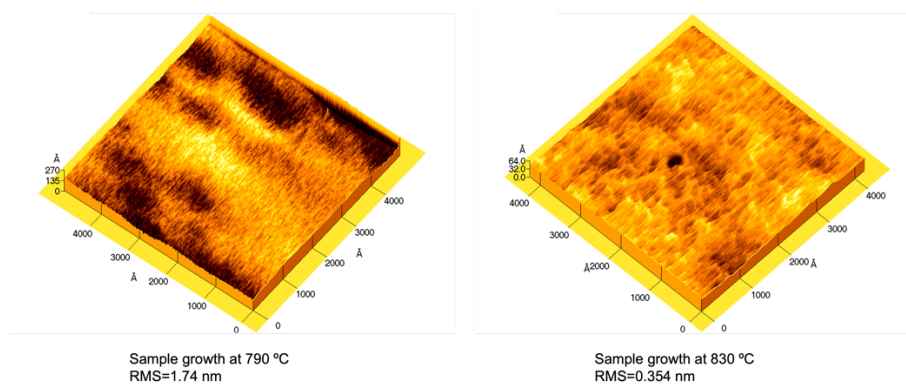


Figure 2. AFM surface micrographs of samples grown at 790 and 830 °C.

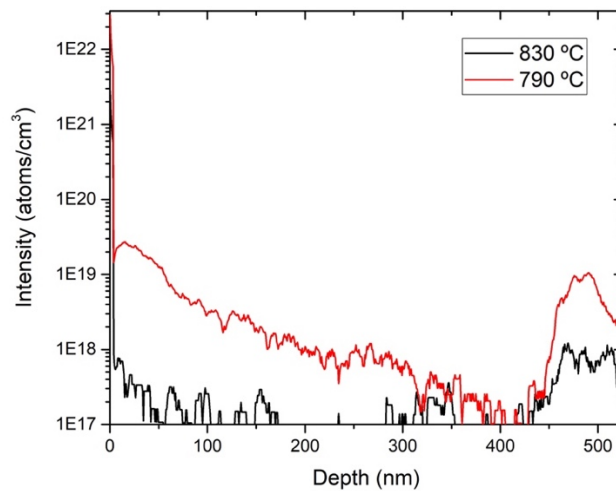


Figure 3. SIMS depth profile of Mn in the samples grown at 790 and 830 °C.